

最终数据手册

英飞凌工业用耐短路 1200 V TRENCHSTOP™ IGBT 7 技术：碳化硅 MOSFET

特性

- $V_{CE} = 1200\text{ V}$
- $I_C = 3\text{ A}$
- 低饱和电压 $V_{CEsat} = 2\text{ V}$ at $T_{vj} = 150^\circ\text{C}$
- 短路耐受性 $8\text{ }\mu\text{s}$
- 广泛的 dv/dt 可控性
- 完整的产品范围和 PSpice 模型：<http://www.infineon.com/igbt/>

潜在应用

- 工业驱动

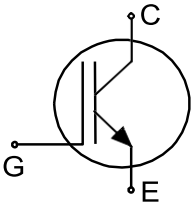
产品验证

- 符合 JEDEC47/20/22 相关测试的工业应用要求
- 所需应用的封装

描述

封装引脚定义：

- 引脚 1 - 栅极
- 引脚 2 (E) - 发射器
- TAB (C) - 收集器



Type	Package	Marking
IGB03N120S7	PG-TO263-3-STD-C1.6	G03MS7

本数据手册的原文使用英文撰写。为方便起见，英飞凌提供了译文；由于翻译过程中可能使用了自动化工具，英飞凌不保证译文的准确性。为确认准确性，请务必访问 [infineon.com](http://www.infineon.com) 参考最新的英文版本（控制文档）。



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1封装

1 封装

表1 特征值

Parameter	Symbol	Note or test condition	Values			Unit
			Min.	Typ.	Max.	
Internal emitter inductance measured 5 mm (0.197 in.) from case	L_E			7		nH
Storage temperature	T_{stg}		-55		150	°C
Soldering temperature	T_{sold}	reflow soldering (MSL1 according to JEDEC J-STA-020)			260	°C
Thermal resistance, 6 cm ² Cu on PCB junction to ambient	$R_{th(j-a)}$				40	K/W
IGBT thermal resistance, junction-case	$R_{th(j-c)}$			2.51	3.39	K/W

2 绝缘栅双极晶体管

表2 最大额定值

Parameter	Symbol	Note or test condition		Values	Unit
Collector-emitter voltage	V_{CE}	$T_{vj} \geq 25\text{ °C}$		1200	V
DC collector current, limited by T_{vjmax}	I_C		$T_c = 25\text{ °C}$	9	A
			$T_c = 100\text{ °C}$	5	
Pulsed collector current, t_p limited by T_{vjmax}	I_{Cpulse}			9	A
Turn-off safe operating area		$V_{CE} \leq 1200\text{ V}, T_{vj} \leq 150\text{ °C}$		9	A
Gate-emitter voltage	V_{GE}			± 20	V
Transient gate-emitter voltage	V_{GE}	$t_p \leq 0.5\text{ }\mu\text{s}, D < 0.001$		± 25	V
Short-circuit withstand time	t_{SC}	$V_{CC} \leq 600\text{ V}, V_{GE} = 15\text{ V}$, Allowed number of short circuits < 1000, Time between short circuits $\geq 1.0\text{ s}, T_{vj} = 150\text{ °C}$		8	μs
Power dissipation	P_{tot}		$T_c = 25\text{ °C}$	37	W
			$T_c = 100\text{ °C}$	15	

表3 特征值

Parameter	Symbol	Note or test condition		Values			Unit
				Min.	Typ.	Max.	
Collector-emitter saturation voltage	V_{CEsat}	$I_C = 3\text{ A}$, $V_{GE} = 15\text{ V}$	$T_{vj} = 25\text{ °C}$		1.65	2	V
			$T_{vj} = 150\text{ °C}$		2		
Gate-emitter threshold voltage	V_{GEth}	$I_C = 0.06\text{ mA}$, $V_{CE} = V_{GE}$		5.15	5.7	6.45	V
Zero gate-voltage collector current	I_{CES}	$V_{CE} = 1200\text{ V}$, $V_{GE} = 0\text{ V}$	$T_{vj} = 25\text{ °C}$			20	μA
			$T_{vj} = 150\text{ °C}$		80		
Gate-emitter leakage current	I_{GES}	$V_{CE} = 0\text{ V}$, $V_{GE} = 20\text{ V}$				100	nA
Transconductance	g_{fs}	$I_C = 3\text{ A}$, $V_{CE} = 20\text{ V}$, $T_{vj} = 150\text{ °C}$			1.8		S
Short-circuit collector current	I_{SC}	$V_{CC} \leq 600\text{ V}$, $V_{GE} = 15\text{ V}$, $t_{SC} \leq 8\text{ }\mu\text{s}$, Allowed number of short circuits < 1000, Time between short circuits $\geq 1.0\text{ s}$, $T_{vj} = 150\text{ °C}$			15		A
Input capacitance	C_{ies}	$V_{CE} = 25\text{ V}$, $V_{GE} = 0\text{ V}$, $f = 100\text{ kHz}$			0.5		nF
Output capacitance	C_{oes}	$V_{CE} = 25\text{ V}$, $V_{GE} = 0\text{ V}$, $f = 100\text{ kHz}$			18		pF
Reverse transfer capacitance	C_{res}	$V_{CE} = 25\text{ V}$, $V_{GE} = 0\text{ V}$, $f = 100\text{ kHz}$			2		pF
Gate charge	Q_G	$V_{CC} = 960\text{ V}$, $I_C = 3\text{ A}$, $V_{GE} = 15\text{ V}$			24		nC
Turn-on delay time	$t_{d(on)}$	$V_{CC} = 600\text{ V}$, $V_{GE} = 0/15\text{ V}$, $R_{G(on)} = 60\text{ }\Omega$, $R_{G(off)} = 60\text{ }\Omega$	$T_{vj} = 25\text{ °C}$, $I_C = 3\text{ A}$		19		ns
			$T_{vj} = 150\text{ °C}$, $I_C = 3\text{ A}$		18		
Rise time (inductive load)	t_r	$V_{CC} = 600\text{ V}$, $V_{GE} = 0/15\text{ V}$, $R_{G(on)} = 60\text{ }\Omega$, $R_{G(off)} = 60\text{ }\Omega$	$T_{vj} = 25\text{ °C}$, $I_C = 3\text{ A}$		15		ns
			$T_{vj} = 150\text{ °C}$, $I_C = 3\text{ A}$		18		
Turn-off delay time	$t_{d(off)}$	$V_{CC} = 600\text{ V}$, $V_{GE} = 0/15\text{ V}$, $R_{G(on)} = 60\text{ }\Omega$, $R_{G(off)} = 60\text{ }\Omega$	$T_{vj} = 25\text{ °C}$, $I_C = 3\text{ A}$		89		ns
			$T_{vj} = 150\text{ °C}$, $I_C = 3\text{ A}$		142		
Fall time (inductive load)	t_f	$V_{CC} = 600\text{ V}$, $V_{GE} = 0/15\text{ V}$, $R_{G(on)} = 60\text{ }\Omega$, $R_{G(off)} = 60\text{ }\Omega$	$T_{vj} = 25\text{ °C}$, $I_C = 3\text{ A}$		203		ns
			$T_{vj} = 150\text{ °C}$, $I_C = 3\text{ A}$		272		
Turn-on energy	E_{on}	$V_{CC} = 600\text{ V}$, $V_{GE} = 0/15\text{ V}$, $R_{G(on)} = 60\text{ }\Omega$, $R_{G(off)} = 60\text{ }\Omega$	$T_{vj} = 25\text{ °C}$, $I_C = 3\text{ A}$		0.21		mJ
			$T_{vj} = 150\text{ °C}$, $I_C = 3\text{ A}$		0.29		
Turn-off energy	E_{off}	$V_{CC} = 600\text{ V}$, $V_{GE} = 0/15\text{ V}$, $R_{G(on)} = 60\text{ }\Omega$, $R_{G(off)} = 60\text{ }\Omega$	$T_{vj} = 25\text{ °C}$, $I_C = 3\text{ A}$		0.16		mJ
			$T_{vj} = 150\text{ °C}$, $I_C = 3\text{ A}$		0.27		

(表格续下页.....)



表 3 (续) 特征值

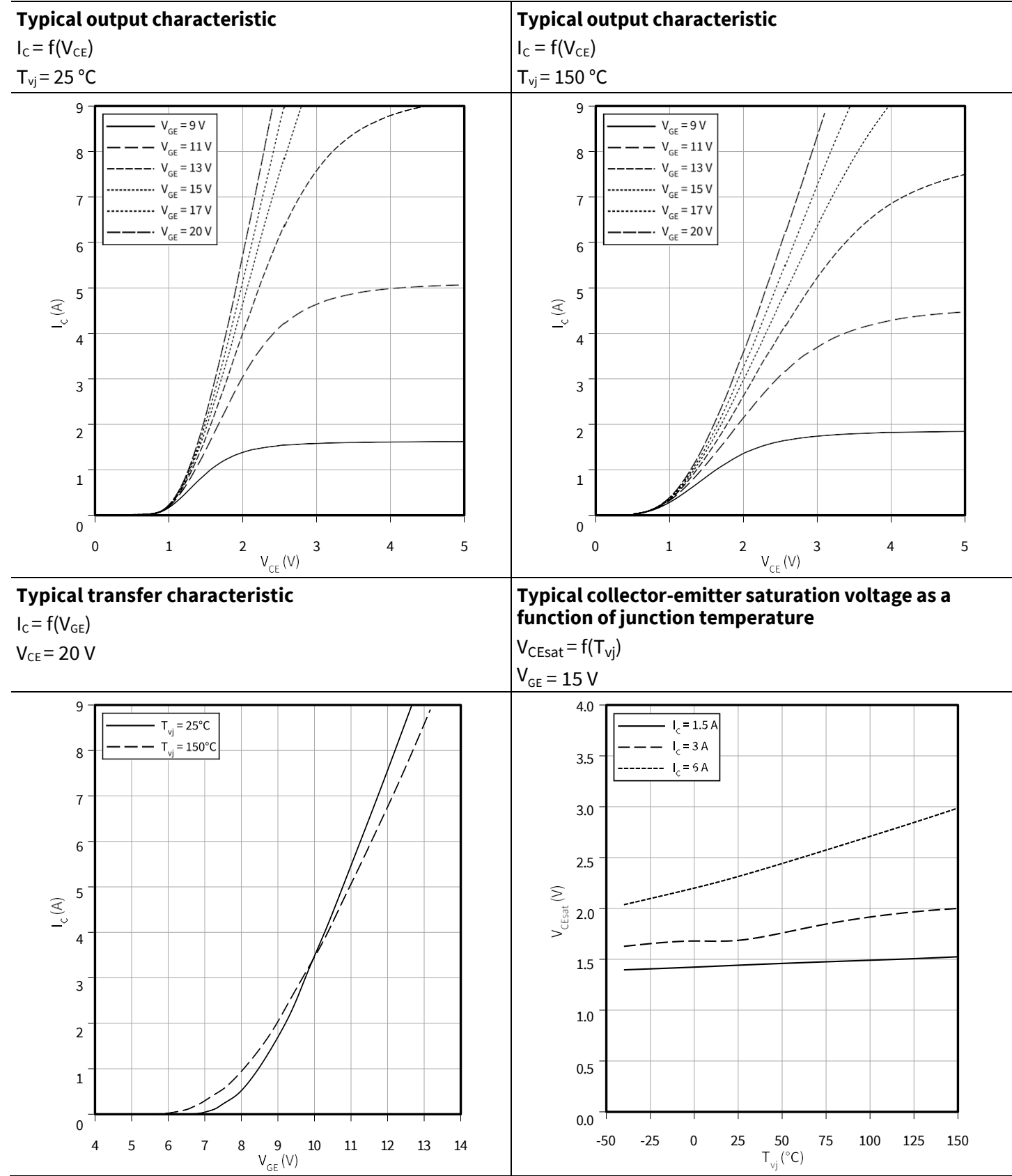
Parameter	Symbol	Note or test condition		Values			Unit
				Min.	Typ.	Max.	
Total switching energy	E_{ts}	$V_{CC} = 600\text{ V}, V_{GE} = 0/15\text{ V},$ $R_{G(on)} = 60\ \Omega,$ $R_{G(off)} = 60\ \Omega$	$T_{vj} = 25\text{ }^{\circ}\text{C}, I_C = 3\text{ A}$		0.37		mJ
			$T_{vj} = 150\text{ }^{\circ}\text{C},$ $I_C = 3\text{ A}$		0.56		
Operating junction temperature	T_{vj}			-40		150	$^{\circ}\text{C}$

注意：为了获得最佳的使用寿命和可靠性，英飞凌建议工作条件不超过本数据手册中所述最大额定值的 80%。

除非另有规定，电气特性均为 $T_{vj} = 25^{\circ}\text{C}$ 。

动态测试电路，寄生电感 $L_{\sigma} = 45\text{ nH}$ ，寄生电容 $C_{\sigma} = 25\text{ pF}$ ，来自图 E。能量损失包括“尾部”和二极管反向恢复。

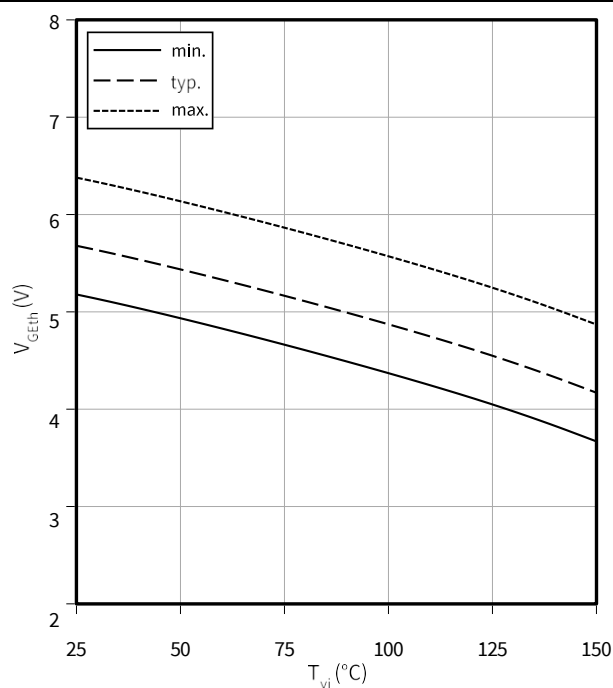
3 特征图



Gate-emitter threshold voltage as a function of junction temperature

$$V_{GEth} = f(T_{vj})$$

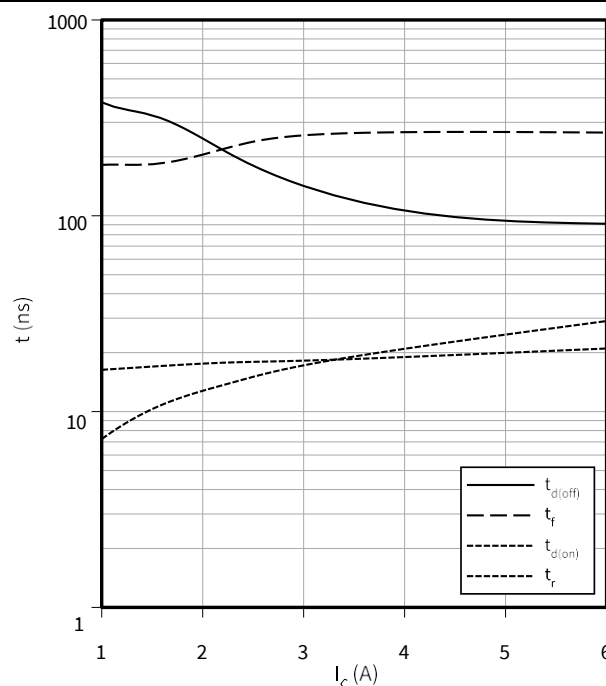
$I_C = 0.06 \text{ mA}$



Typical switching times as a function of collector current

$$t = f(I_C)$$

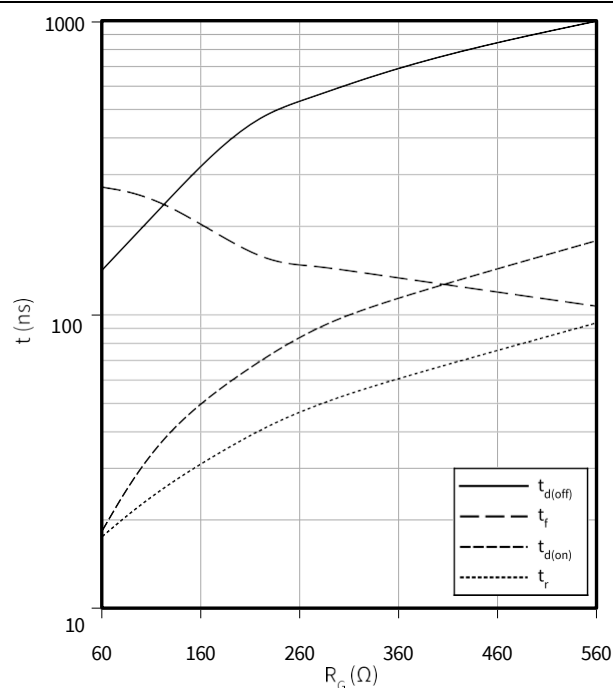
$V_{CC} = 600 \text{ V}$, $T_{vj} = 150 \text{ }^\circ\text{C}$, $V_{GE} = 0/15 \text{ V}$, $R_G = 60 \text{ } \Omega$



Typical switching times as a function of gate resistor

$$t = f(R_G)$$

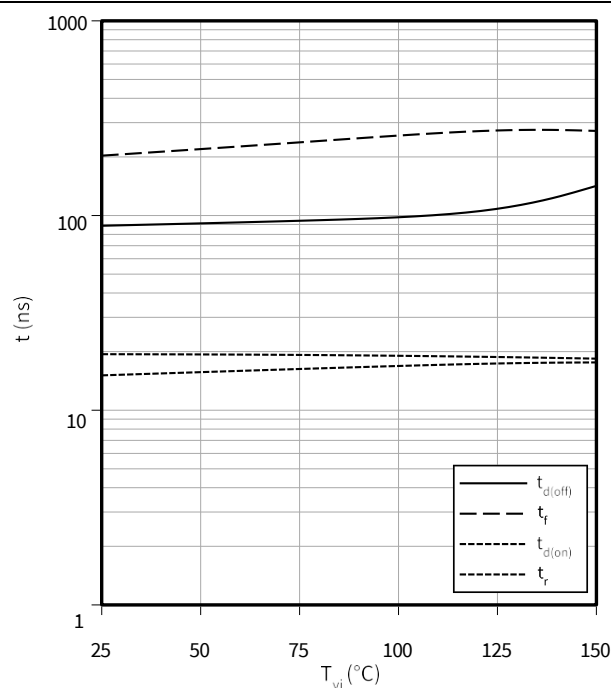
$I_C = 3 \text{ A}$, $V_{CC} = 600 \text{ V}$, $T_{vj} = 150 \text{ }^\circ\text{C}$, $V_{GE} = 0/15 \text{ V}$



Typical switching times as a function of junction temperature

$$t = f(T_{vj})$$

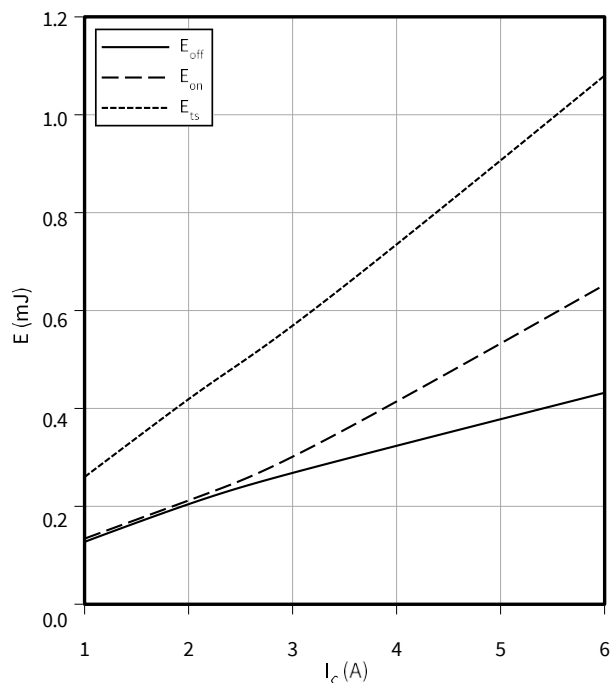
$I_C = 3 \text{ A}$, $V_{CC} = 600 \text{ V}$, $V_{GE} = 0/15 \text{ V}$, $R_G = 60 \text{ } \Omega$



Typical switching energy losses as a function of collector current

$$E = f(I_C)$$

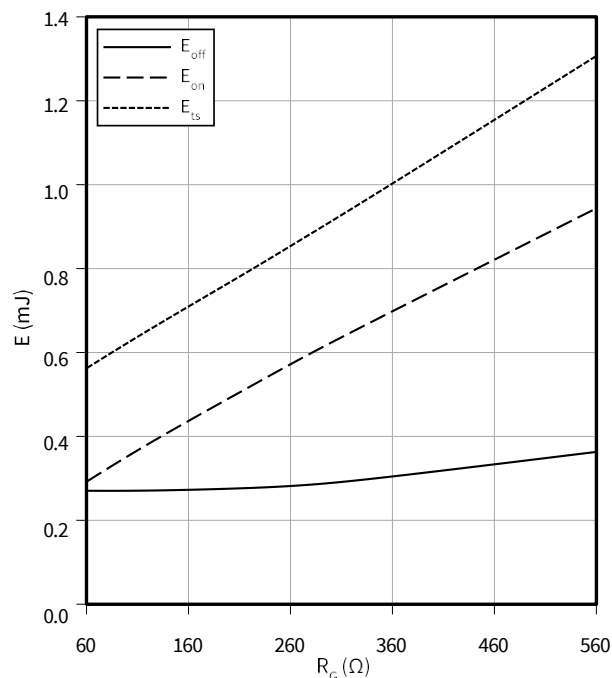
$V_{CC} = 600 \text{ V}$, $T_{vj} = 150 \text{ °C}$, $V_{GE} = 0/15 \text{ V}$, $R_G = 60 \text{ } \Omega$



Typical switching energy losses as a function of gate resistor

$$E = f(R_G)$$

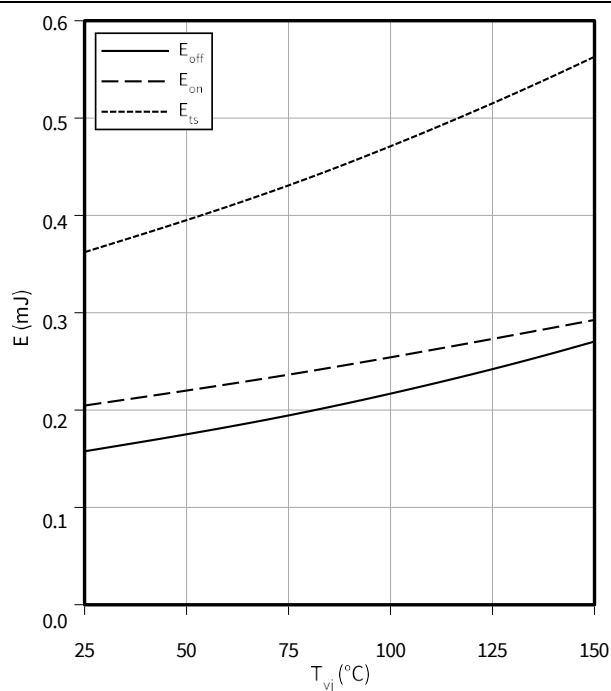
$I_C = 3 \text{ A}$, $V_{CC} = 600 \text{ V}$, $T_{vj} = 150 \text{ °C}$, $V_{GE} = 0/15 \text{ V}$



Typical switching energy losses as a function of junction temperature

$$E = f(T_{vj})$$

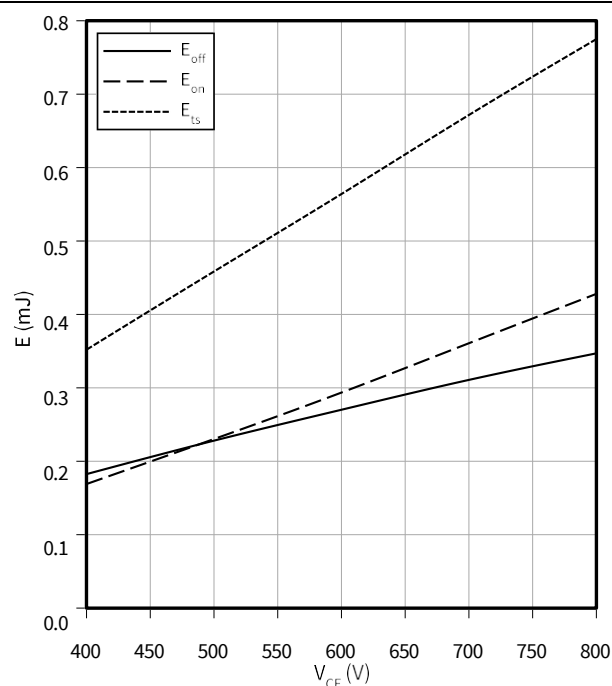
$I_C = 3 \text{ A}$, $V_{CC} = 600 \text{ V}$, $V_{GE} = 0/15 \text{ V}$, $R_G = 60 \text{ } \Omega$



Typical switching energy losses as a function of collector emitter voltage

$$E = f(V_{CE})$$

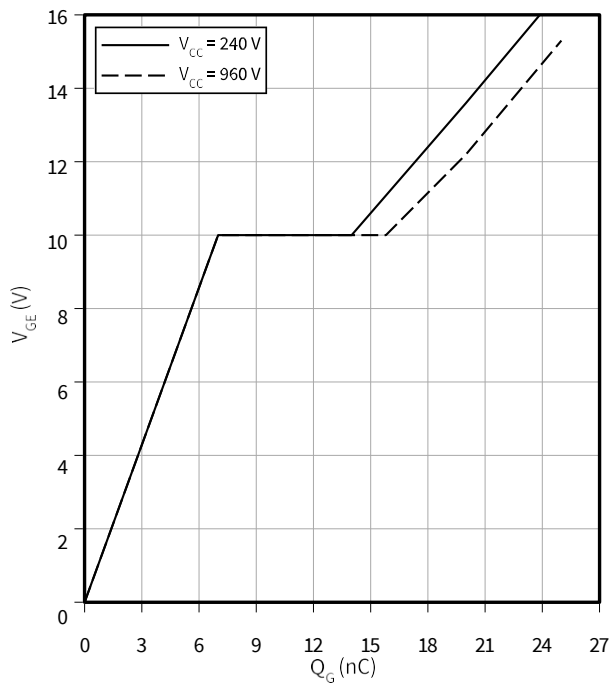
$I_C = 3 \text{ A}$, $T_{vj} = 150 \text{ °C}$, $V_{GE} = 0/15 \text{ V}$, $R_G = 60 \text{ } \Omega$



Typical gate charge

$$V_{GE} = f(Q_G)$$

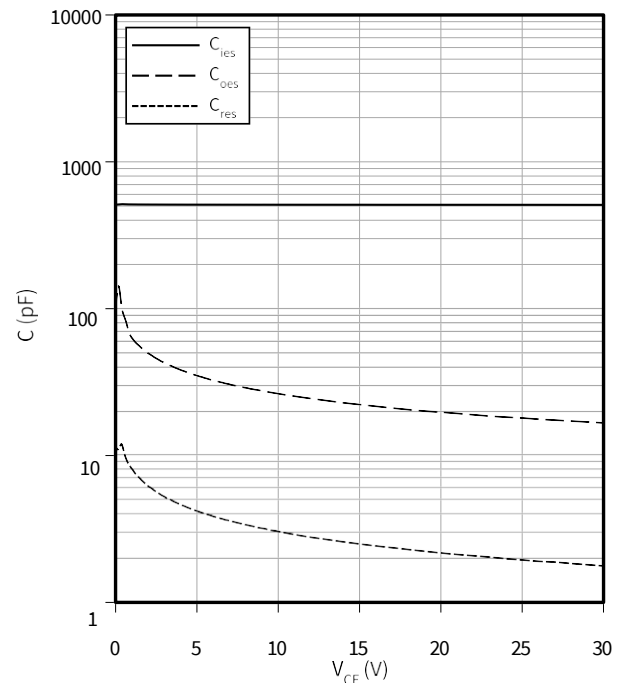
$$I_C = 3 \text{ A}$$



Typical capacitance as a function of collector-emitter voltage

$$C = f(V_{CE})$$

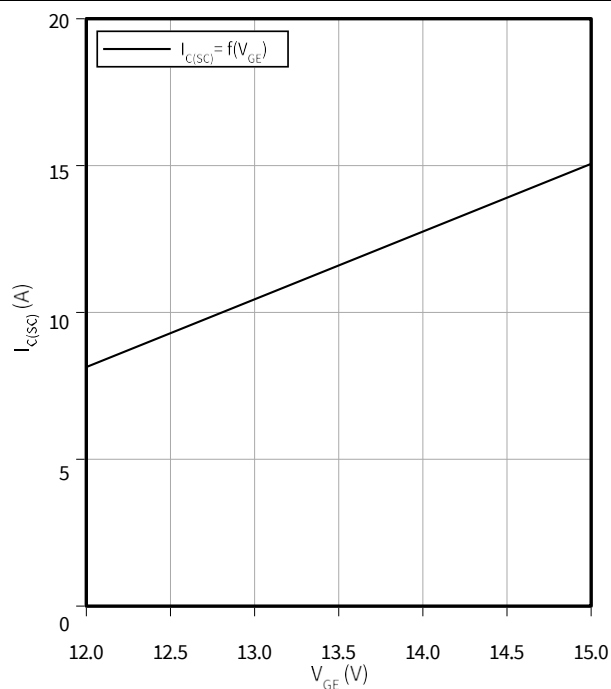
$$f = 100 \text{ kHz}, V_{GE} = 0 \text{ V}$$



Typical short circuit collector current as a function of gate-emitter voltage

$$I_{C(SC)} = f(V_{GE})$$

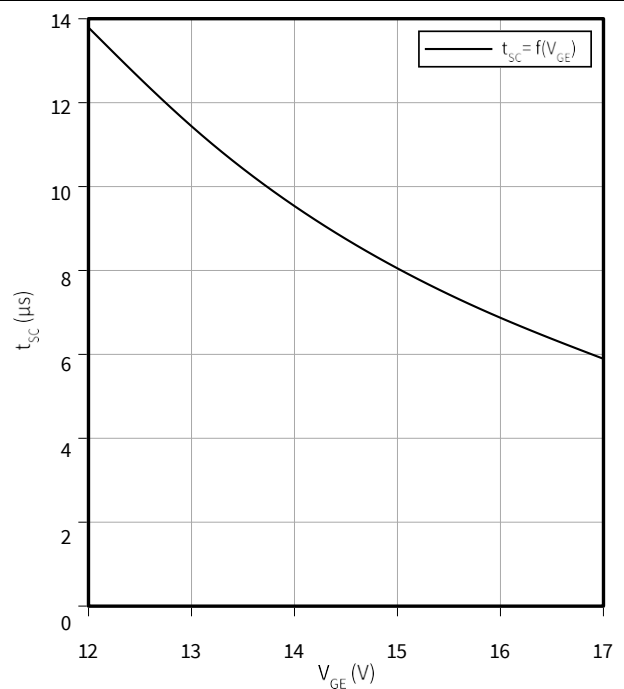
$$T_{vj} = 150 \text{ °C}, V_{CC} = 600 \text{ V}$$



Short circuit withstand time as a function of gate-emitter voltage

$$t_{SC} = f(V_{GE})$$

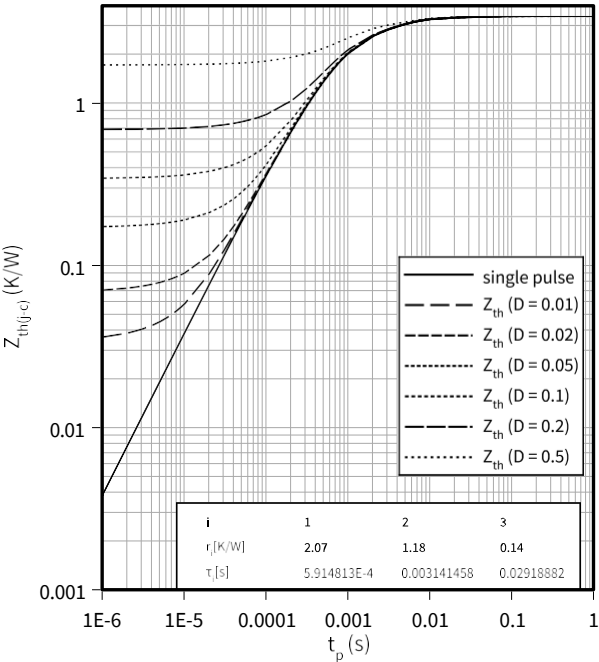
$$T_{vj} = 150 \text{ °C}, V_{CC} = 600 \text{ V}$$



IGBT transient thermal impedance as a function of pulse width

$Z_{th(j-c)} = f(t_p)$

$D = t_p/T$



4 封装外形

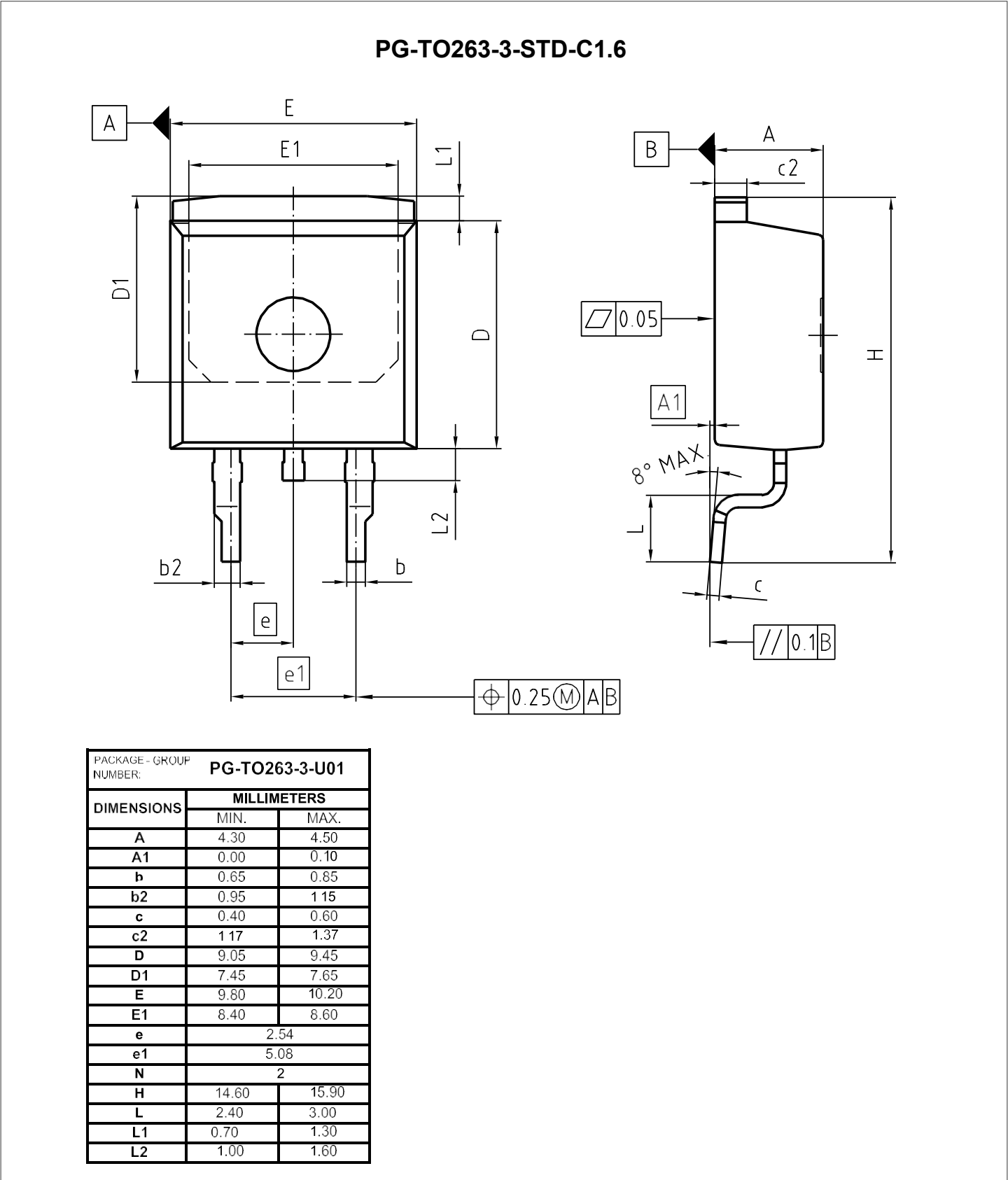


图 1

5 测试条件

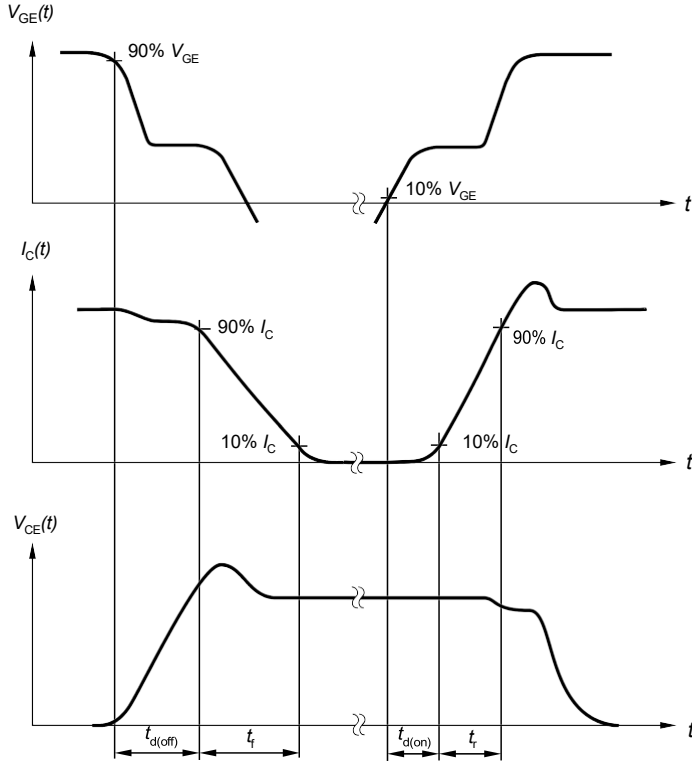


Figure A. Definition of switching times

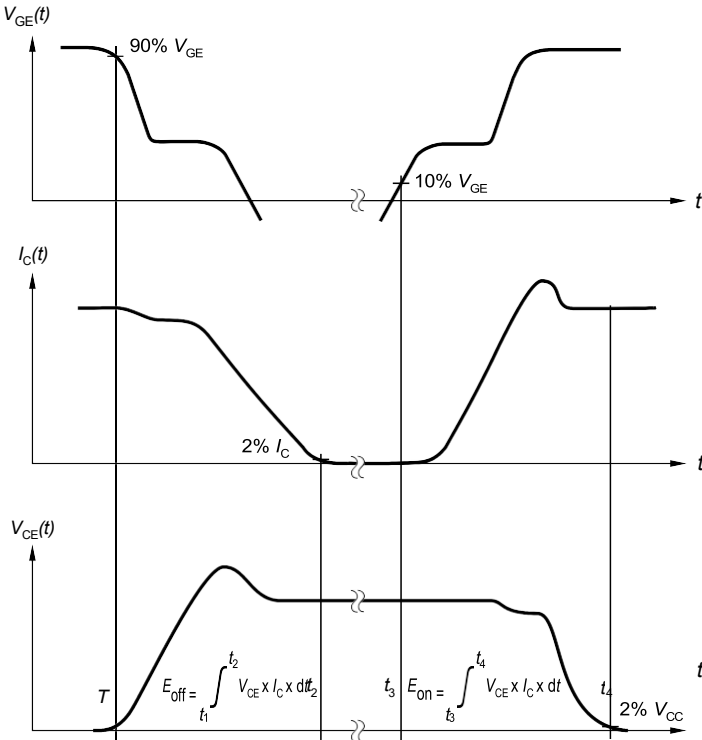


Figure B. Definition of switching

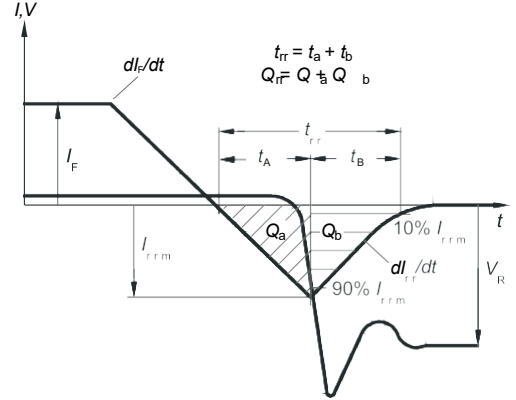


Figure C. Definition of diode switching characteristics

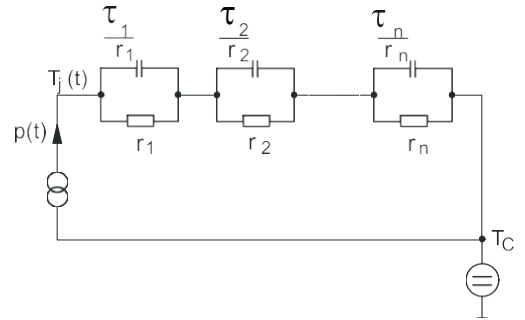


Figure D. Thermal equivalent circuit

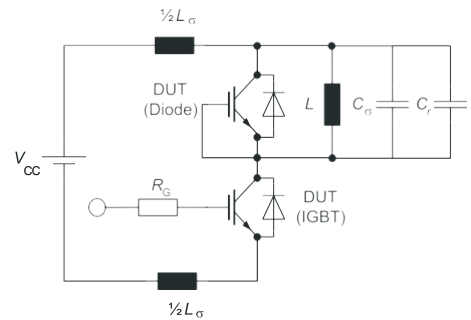


Figure E. Dynamic test circuit

Parasitic inductance L_{σ} ,
parasitic capacitor C_{σ} ,
relief capacitor C_r ,
(only for ZVT switching)

修订记录

修订记录

Document revision	Date of release	Description of changes
1.00	2024-03-11	Final datasheet



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